

2018 IEEE International Test Conference (ITC 2018)

**Phoenix, Arizona, USA
29 October – 1 November 2018**



**IEEE Catalog Number: CFP18ITC-POD
ISBN: 978-1-5386-8383-5**

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IEEE Catalog Number:	CFP18ITC-POD
ISBN (Print-On-Demand):	978-1-5386-8383-5
ISBN (Online):	978-1-5386-8382-8
ISSN:	1089-3539

Additional Copies of This Publication Are Available From:

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